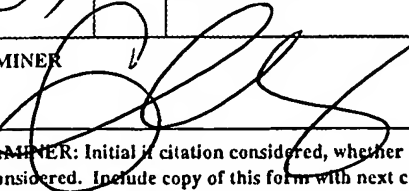


<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>		Docket Number (Optional) <b>UC01-161-2</b>	Application Number <b>10/039,290</b>
		Applicant(s) <b>ALI SHAKOURI ET AL.</b>	
Filing Date <b>JANUARY 4, 2002</b>		Group Art Unit <b>9836 2627</b>	

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\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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